


<b>Search Notes</b>  	<b>Application/Control No.</b>  10826090	<b>Applicant(s)/Patent Under Reexamination</b>  CHEN, SHI-SHIEN
	<b>Examiner</b>  Neway, Samuel G	<b>Art Unit</b>  2626

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST: Text, Assignee, Inventor, Forward & Backward, and PLUS Search	08/14/07	SN
Consulted: P. Edouard	08/14/07	SN
Consulted: T. Smits	08/15/07	SN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner